

<b>Notice of References Cited</b>	Application/Control No. 10/664,012	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Marc Jimenez	Art Unit 3726	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,696,158	02-2004	Chen et al.	428/421
	B	US-5,323,702	06-1994	Vrotacoe et al.	101/217
	C	US-5,716,714	02-1998	Chen et al.	428/473.5
	D	US-5,736,250	04-1998	Heeks et al.	428/447
	E	US-6,355,352	03-2002	Chen et al.	428/421
	F	US-2002/0002921	01-2002	Hoffmann et al.	101/376
	G	US-2002/0134264	09-2002	Okubo et al.	101/401.1
	H	US-6,393,247	05-2002	Chen et al.	399/330
	I	US-6,716,502	04-2004	Badesha et al.	428/35.8
	J	US-6,078,778	06-2000	Murata et al.	399/313
	K	US-5,918,098	06-1999	Van Bennekom, Hans Lochmann	399/333
	L	US-6,393,226	05-2002	Charlebois et al.	399/12
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.